

Astronomical Techniques II

Lecture 11 - Sensitivity and Deconvolution

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Noise and Temperature

1 $P = kT\Delta\nu$

2 $P_N = kT_{sys}\Delta\nu G$

$$T_{sys} = T_{bg} + T_{atm} + T_{spill} + T_{loss} + T_{rec}$$

Everything but the target source

3 $P_a = kT_a\Delta\nu G$

T_a - contribution from the target source

4 $T_{a1} = \frac{\eta_{a1}A_1S}{2k} = K_1S$

5 $K = \frac{\eta_a A}{2k} \text{ K Jy}^{-1}$ - Flux collecting ability of an antenna

Sensitivity of a 2 element interferometer

1 $V_1(t) = S_1(t) + n_1(t)$

2 $V_2(t) = S_2(t) + n_2(t)$

3 Assumptions

1 Point source at phase centre

2 Appropriate delays and fringe stop

3 Gaussian white noise

4 Components of the correlated output

1 Constant (DC) - $S_1(t) S_2(t)$ - the object of our measurement

2 zero mean, time varying output - unavoidable noise

Sensitivity of a 2 element interferometer

1 Ratio of DC component to the RMS of the time varying component

2 Derivation based on

1 Wiener-Khinchine theorem

3
$$\Delta S = \frac{1}{\sqrt{\Delta t \Delta \nu}} \sqrt{S^2 + \frac{ST_{sys}}{K} + \frac{T_{sys}^2}{2K^2}}$$

where $K = \frac{\eta_a A}{2k}$

Sensitivity of a 2 element interferometer

1 Weak source case $S \ll \frac{T_{sys}}{K}$

$$\Delta S = \frac{1}{\sqrt{2\Delta t \Delta\nu}} \frac{T_{sys}}{K}$$

2 Strong source case $S \gg \frac{T_{sys}}{K}$

$$\Delta S = \frac{S}{\sqrt{\Delta t \Delta\nu}}$$

Sensitivity of a 2 element complex correlator

1 $S_m = \sqrt{S_R^2 + S_I^2}$

$$\phi_m = \tan^{-1} \frac{S_I}{S_R}$$

- 2** Noise distribution for S_m - Rice distribution

$$P(S_m) = \frac{S_m}{\Delta S^2} I_0 \left(\frac{S_m S}{\Delta S^2} \right) e^{-\frac{(S_m^2 + S^2)}{s \Delta S^2}}$$

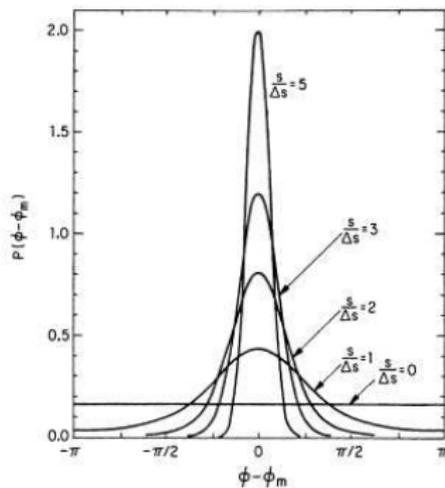
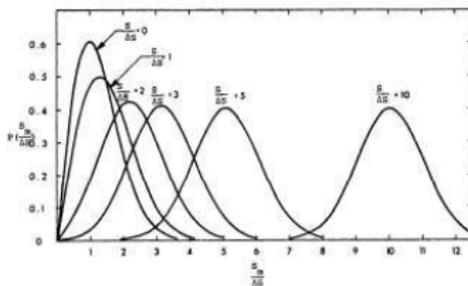
where I_0 is the modified Bessels function of the first kind, order zero, and S is the true amplitude.

- 3** Probability distribution for phase error $\phi - \phi_m$, where ϕ is the true phase

$$P(\phi - \phi_m) = \frac{1}{2\pi} e^{-\frac{S^2}{2 \Delta S^2}} \left(1 + G \sqrt{\pi} e^{G^2} (1 + \operatorname{erf} G) \right)$$

where $G(\theta) = \frac{S \cos \theta}{\sqrt{2} \Delta S}$

Probability distribution of measured amplitude and phase



Sensitivity for a point source

$$1 \quad \Delta I_m = \frac{\sqrt{2}kT_{sys}}{\eta_a \eta_c A \sqrt{N_{base} N_{IF} \Delta T \Delta \nu}}$$

$$2 \quad \eta_c = \frac{\textit{Sensitivity of the correlator}}{\textit{Sensitivity of a perfect analog correlator}}$$

1 bit - 64%; 2 bit 3 level - 81%

Sensitivity for an extended source

1 $B(l, m) - Jy \text{ beam}^{-1}$

2 $\frac{l \Omega_s}{\Delta l_m}$

Effect of the primary beam

$$\mathbf{1} \quad I_m(l, m) = I(l, m) P(l, m) + N(l, m)$$

$$\mathbf{2} \quad \frac{I_m(l, m)}{P(l, m)} = I(l, m) + \frac{N(l, m)}{P(l, m)}$$

Deconvolution

- 1 $V'(u, v) = \int \int I(l, m) e^{-2\pi i(ul+vm)} dl dm$
- 2 Direct inversion not possible
- 3 Model with a finite number of parameters
- 4 $\hat{I}(p\Delta l, q\Delta m)$
- 5 $\hat{V}(u, v) = \sum_{p=1}^{N_l} \sum_{q=1}^{N_m} \hat{I}(p\Delta l, q\Delta m) e^{-2\pi i(pu\Delta l + qv\Delta m)}$

1 Range of features which can be captured by the data

1 $\mathcal{O}(1/\max(u, v))$

2 $\mathcal{O}(1/\min(u, v))$

2 Choice of $\Delta l, \Delta m$ and N_l, N_m , must allow these scales to be represented

1 $\Delta l \leq \frac{1}{2u_{\max}}; \Delta m \leq \frac{1}{2v_{\max}}$

2 $N_l \Delta l \geq \frac{1}{u_{\min}}; N_m \Delta m \geq \frac{1}{v_{\min}}$

3 Degrees of Freedom - $N_l \times N_m$

1 $V(u_i, v_i) = \hat{V}(u_i, v_i) + \epsilon(u_i, v_i)$

2 $V(u, v) = W(u, v) \left(\hat{V}(u, v) + \epsilon(u, v) \right)$

3 $W(u, v) = \sum_i W_i \delta(u - u_i, v - v_i)$

4 $I_{p,q}^D = \sum_{p',q'} B_{p-p',q-q'} \hat{I}_{p',q'} + E_{p,q}$ where

$$I_{p,q}^D = \sum_i W(u_i, v_i) \operatorname{Re} \left(V(u_i, v_i) e^{2\pi i (pu_i \Delta l + qv_i \Delta m)} \right) \text{ and}$$

$$B_{p,q} = \sum_i W(u_i, v_i) \operatorname{Re} \left(e^{2\pi i (pu_i \Delta l + 1v_i \Delta m)} \right)$$

Principal Solution and Invisible Distributions

- 1 If some spatial frequencies allowed in the model are not present in the data, changing their amplitudes in the model will have no effect on the fit to the data
- 2 Z - the invisible intensity distribution, then $B \star Z = 0$
- 3 If I is a solution to the convolution eqn, $I + \alpha Z$ is also a solution
- 4 The solution which has 0 amplitude at all unsampled spatial frequencies - principal solution
- 5 The problem of imaging - principal solution + a plausible invisible distribution

The need for *a-priori* information

- 1 Limitations of the Principal solution
 - 1 Changes with data available
 - 2 Sidelobes of order 1-10%
 - 3 Is it a point source or is it a source shaped like the dirty beam
- 2 *A-priori* information
 - 1 Positivity (Stokes I must be positive)
 - 2 Nature of sources (do not have sidelobes extending to infinity)
 - 3 Information of the PSF

The CLEAN Algorithm

- 1 Represent the sky as a collection of point sources in an otherwise empty field of view
- 2 Iterative procedure to find the positions and strengths of these point sources
- 3 Deconvolved image - Supersposition of point source convolved with a CLEAN beam and the residual noise

The Hogbom Clean

- 1 Find the location and the strength of the brightest point in I^D - S_i at (l_i, m_i) and add it to the accumulated point source model $\hat{I}_{p,q}$.
- 2 $I^D - (B^D(l + l_i, m + m_i) \times S_i \times \gamma)$, where $\gamma \ll 1$, usually 0.1
- 3 Iterate till remaining peaks are below some user specified threshold
- 4 Convolve $\hat{I}_{p,q}$ with a *restoring beam* - an idealised beam, usually an elliptical Gaussian fit to the central part of the B^D
- 5 Add the residuals to the restored image - *CLEAN image*

The Clark Clean

- 1** CLEAN involves a lot of shifting, scaling and convolutions
- 2** Minor cycle
 - 1** Choose a beam patch (include highest exterior sidelobes)
 - 2** Select bright points from I^D as before
 - 3** Perform *Hogbom* clean using the beam patch and the selected point sources
- 3** Major cycle
 - 1** Point source model built up in the minor cycle is FFTed, weighted and sampled appropriately and FFTed back to the image domain. This is subtracted from the I^D .
 - 2** Errors introduced due to the use of the beam patch in the minor cycles are corrected at the major cycle stage

The Cotton-Schwab Clean

- 1 The major cycle is performed on *ungridded* visibilities
 - 1 Avoids aliasing and gridding errors
- 1 Some miscellaneous comments about Clean
 - 1 Use of clean *boxes*
 - 2 No. of iterations vs loop gain (γ)
 - 3 The problem of short spacings
 - 4 The choice of restoring beam
 - 5 Clean instabilities
 - 6 Multi-resolution clean
 - 7 Sources lying on pixel boundaries